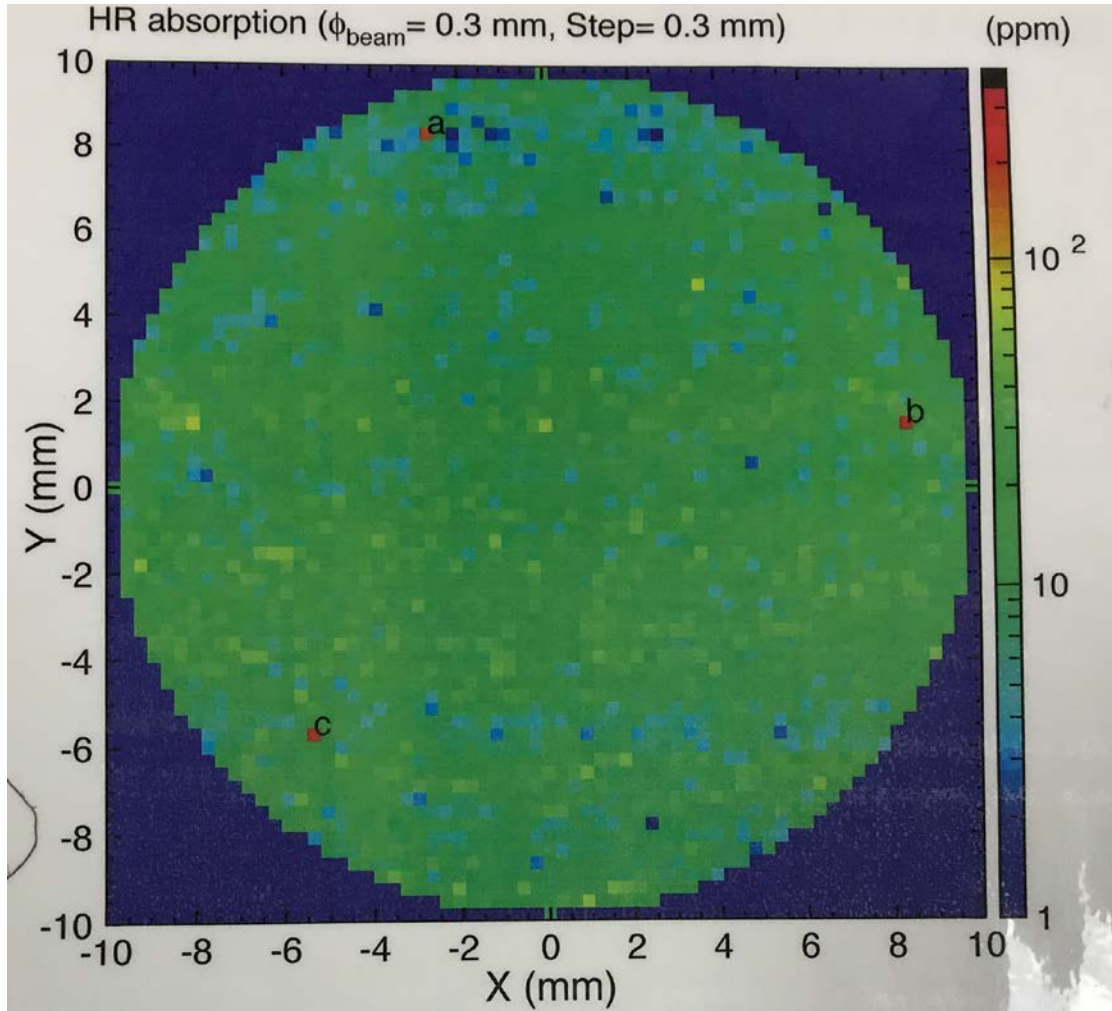


Point absorbers in aLIGO coating

Slawek Gras, Kevin Kuns, and Peter Fritschel

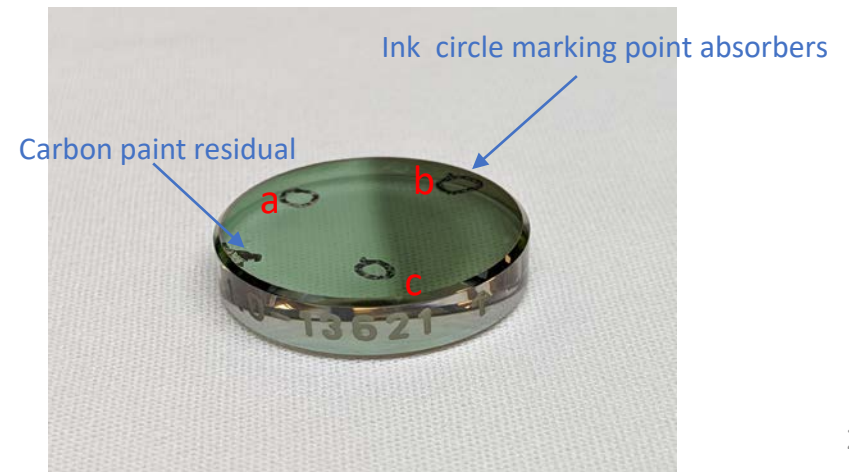
MIT
December 2019

Absorption Map: Caltech



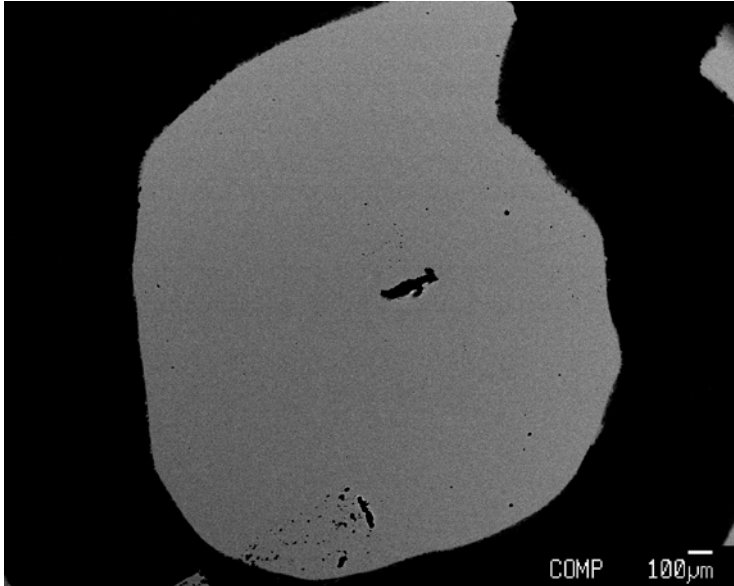
DCC: T1900838

- Witness sample SN#13621 ETM07/09 AR coating
 - material: TiO_2 : Ta_2O_5 / SiO_2
 - total thickness: $\sim 1.6 \mu\text{m}$
- 3 high absorption points identified during abortion measurement :
 - a $\sim 180\text{ppm}$
 - b $\sim 270 \text{ppm}$
 - c $\sim 200 \text{ppm}$
- The origin of the point absorbers unknown until now
- Many absorber candidates identified from the optical inspection are in fact missing coating.
- SEM/EDS/WDS analysis revealed aluminum is a likely absorber candidate.

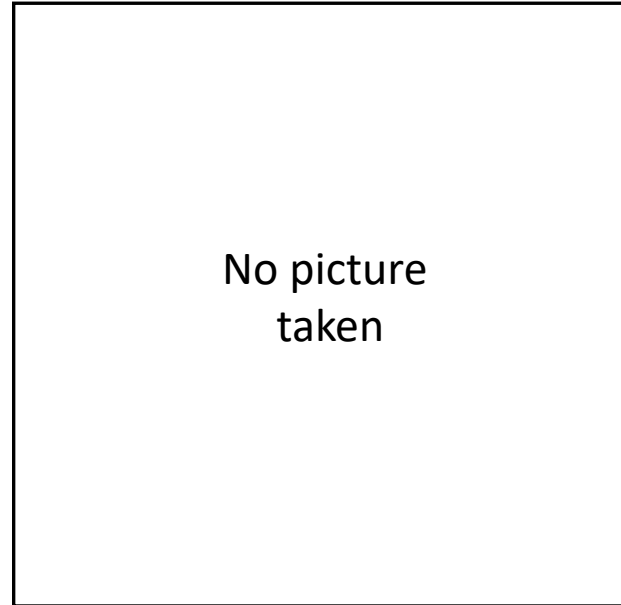


High contrast SEM images

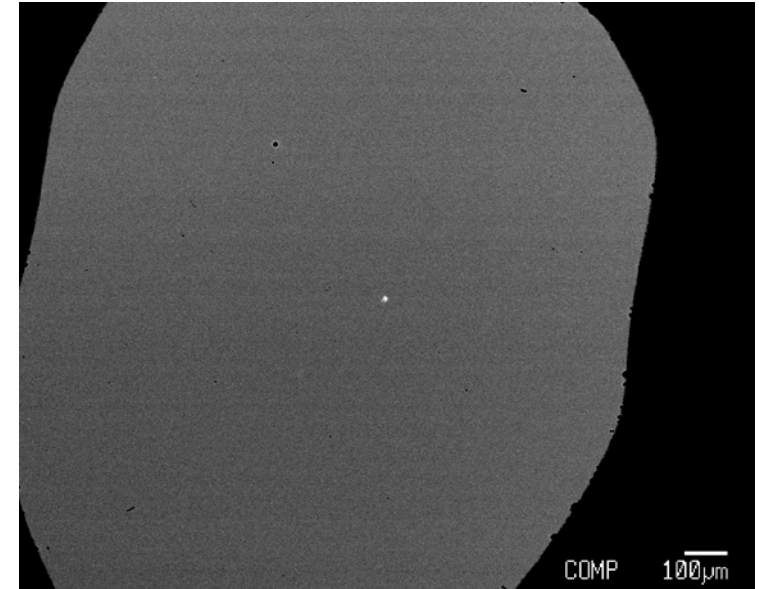
A area



B area



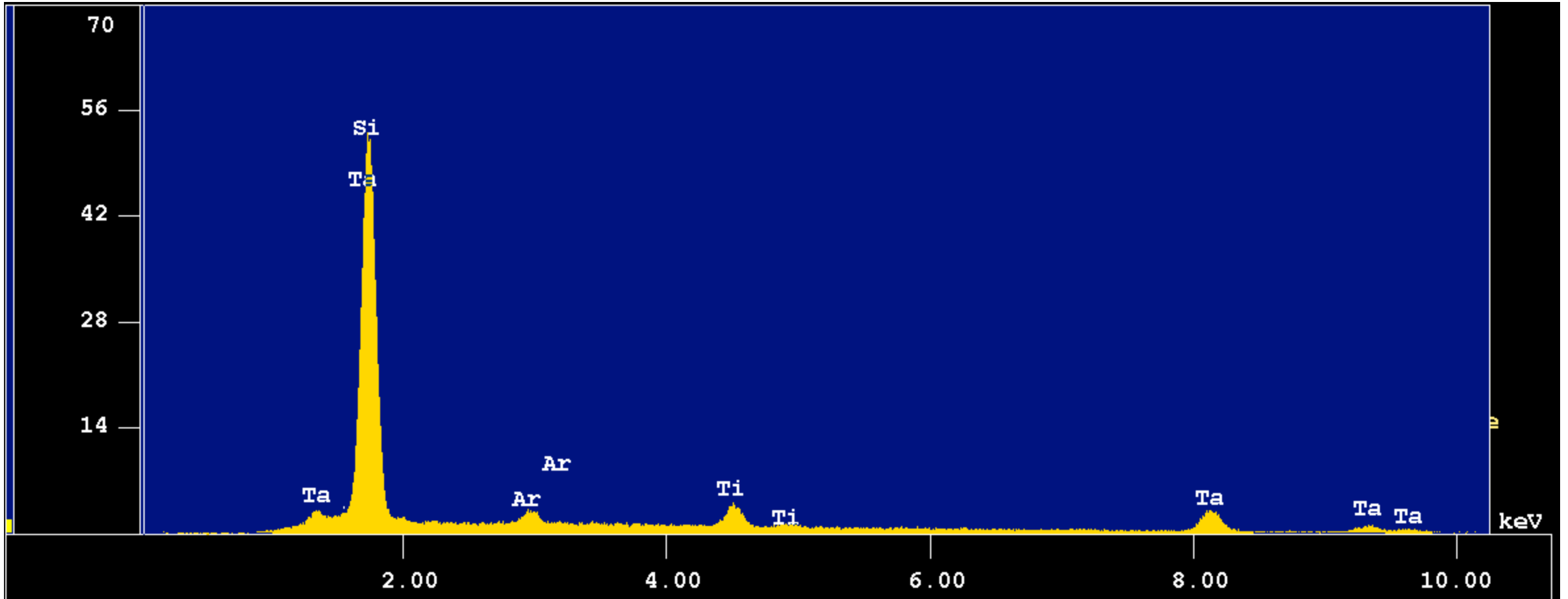
C area



The thick black contours correspond to the ink circles mark areas with high absorption. We left them on the coating.

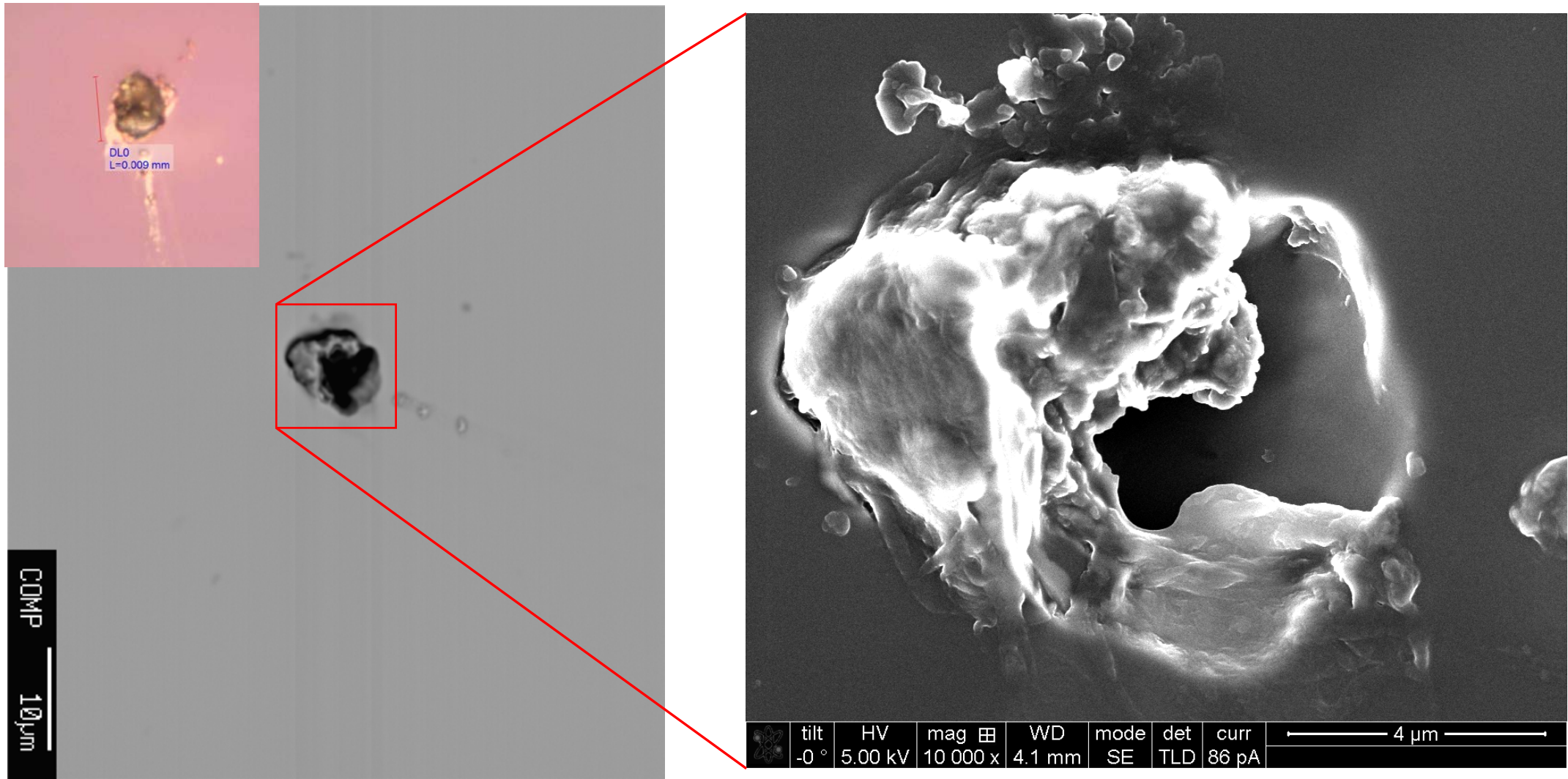
Spectrum of clean coating

From: JEOL JXA-8200 , e-beam: 15 kV, 10 nA



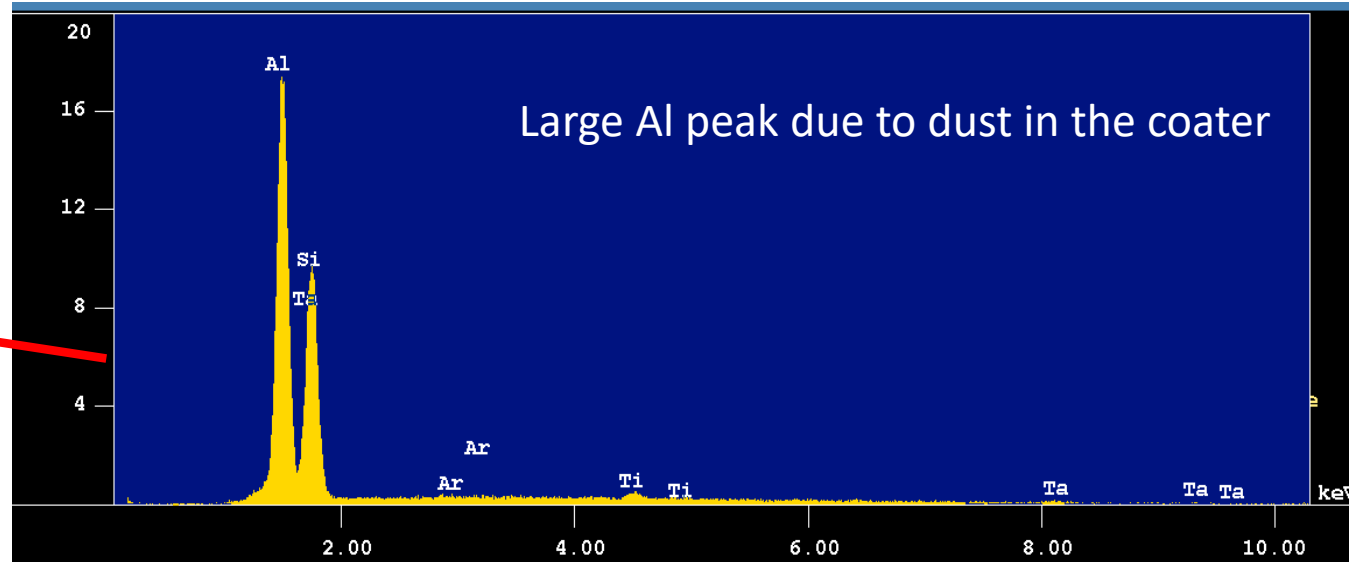
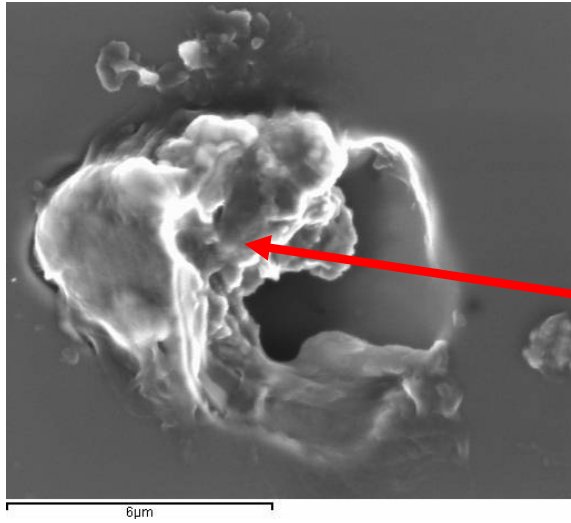
- We see multiple Si, Ta, and Ti lines from the coating
- Trapped Ar lines from IBS plasma
- Oxygen from metal oxides is below 1 keV and too weak to measure with this instrument
- Based on WDS: $Ta/Ti = 78.9/21.1$

Area B, point absorber B1

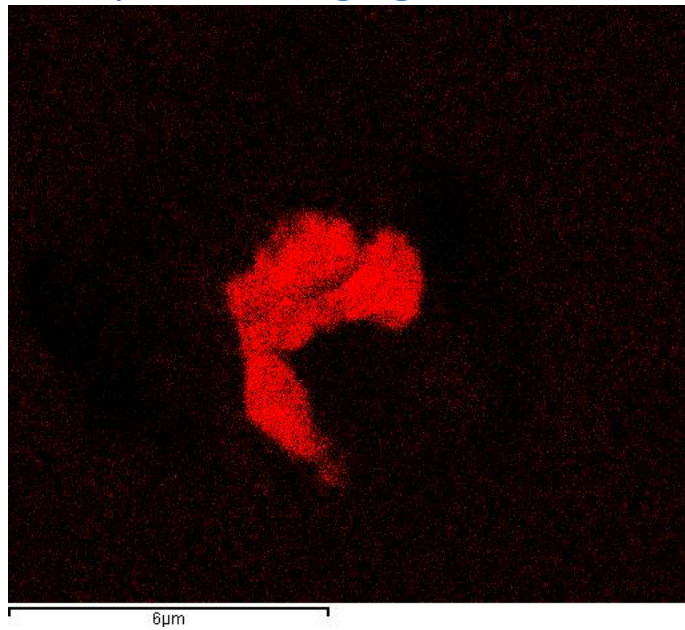


Located in Area B. This defect is of ~ 6 μm in diameter, irregular shape, possibly located in the top layers of the coating

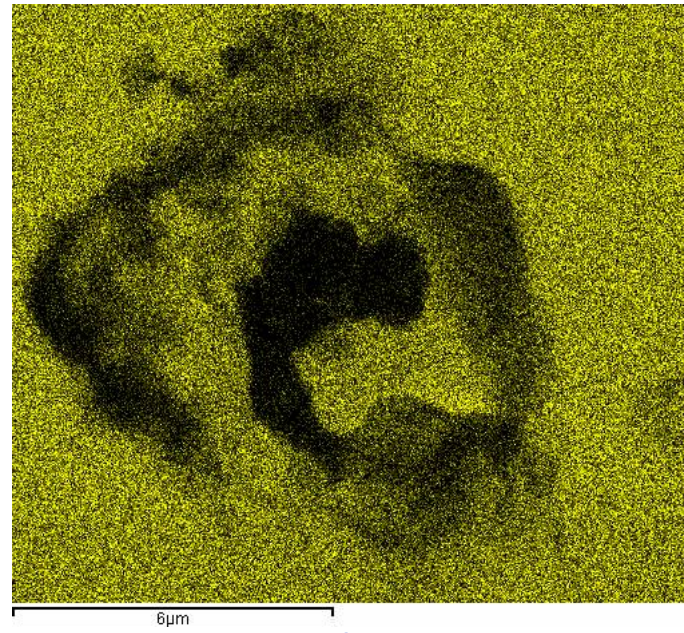
Area B, point absorber B1



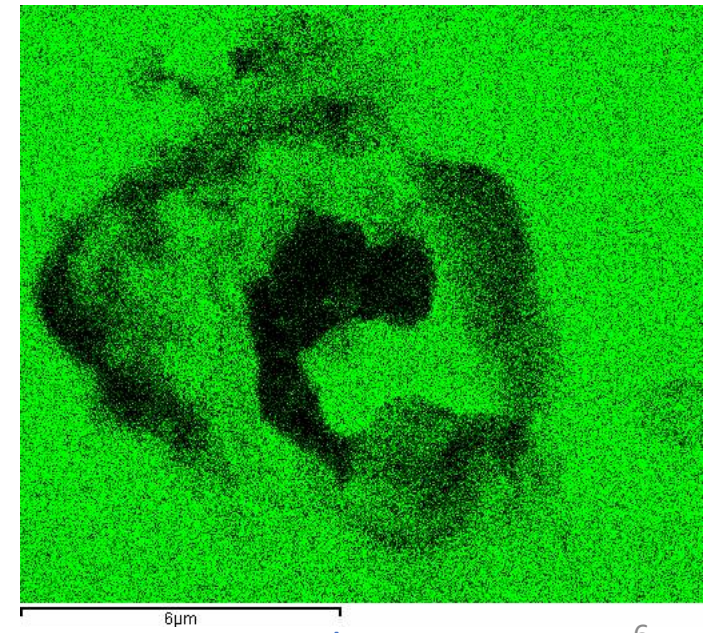
EDS spectral imaging:



Aluminum

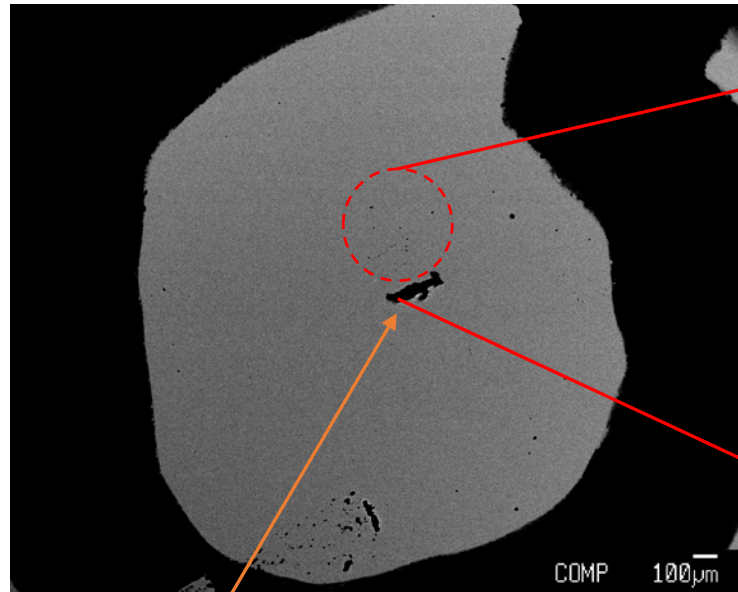


Tantalum



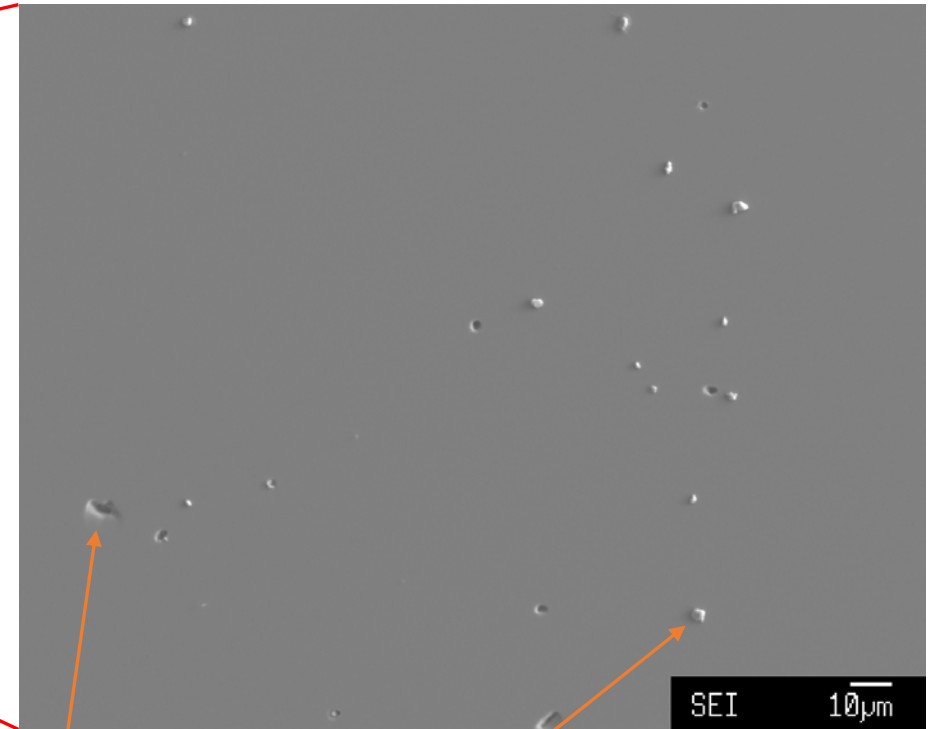
Silicon

Overview of area A



Missing coating previously thought to be a point absorber > 100 µm

Debris field



missing coating < 10 µm

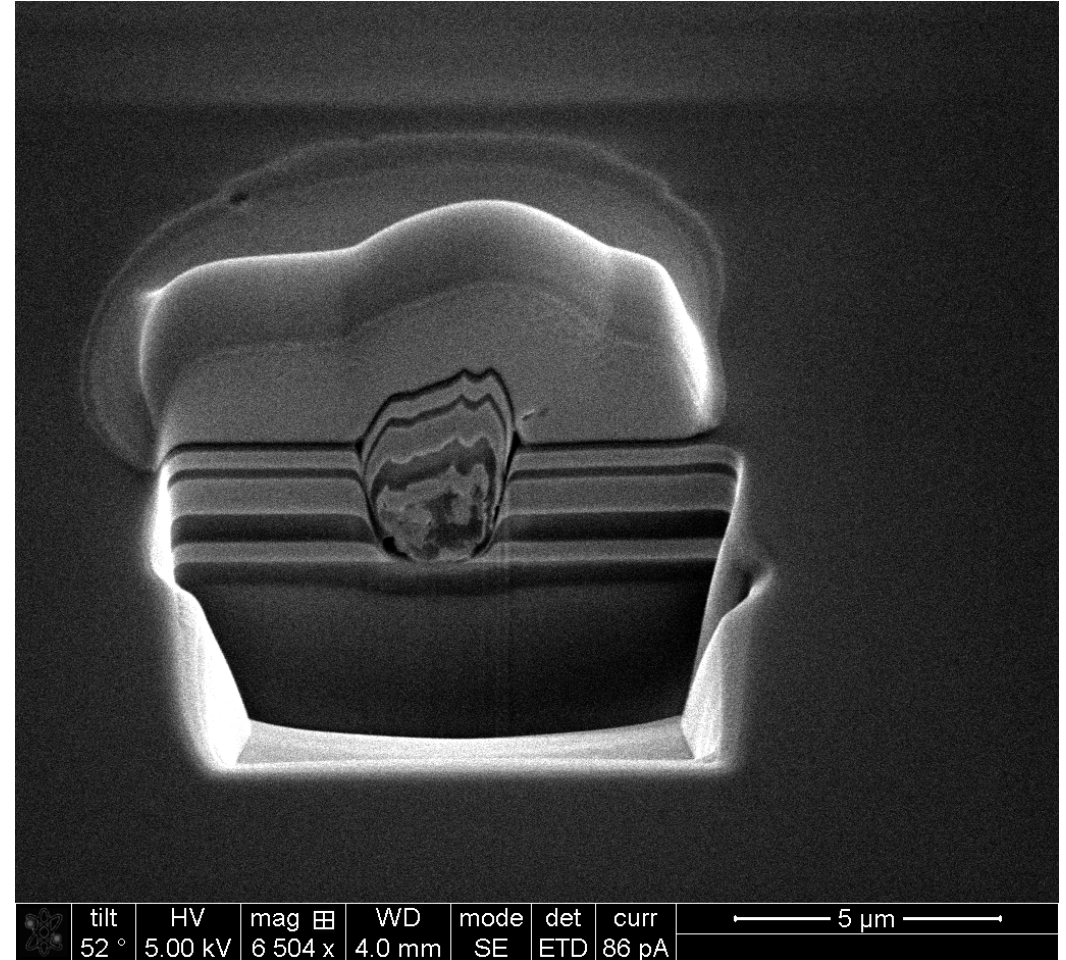
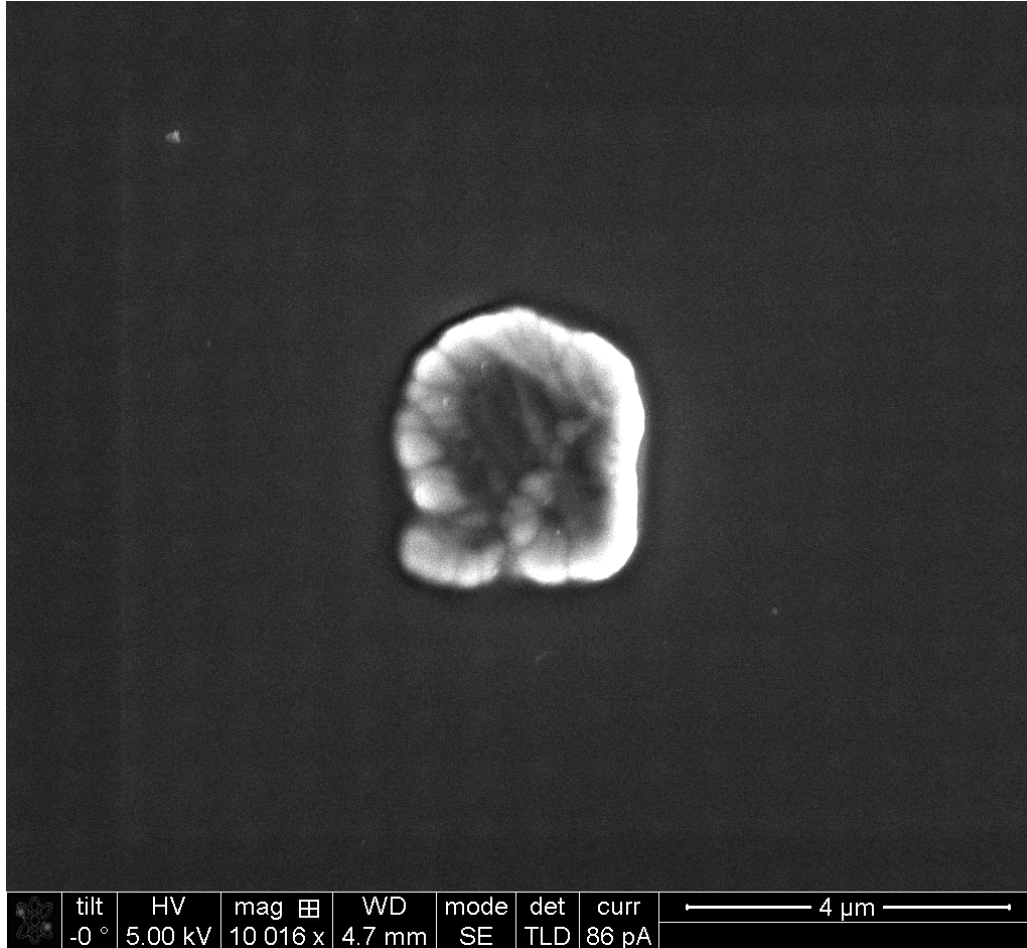
point absorber A1

We observe many defects in this field; possible point absorbers, only one inspected so far

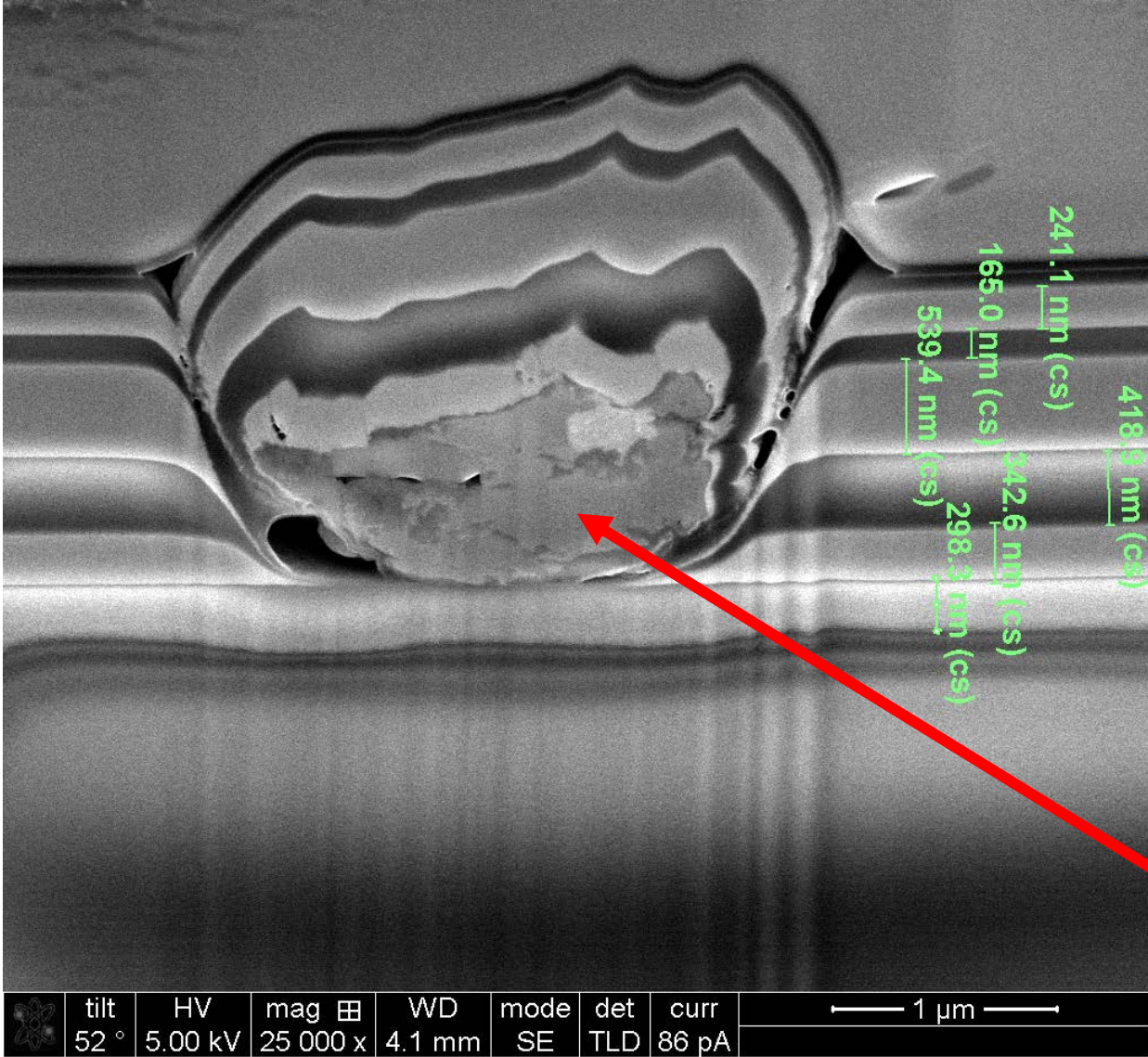
Area A, point absorber A1

- This defect appears to be part of the coating; it does not look like a particle on the surface
- Spectrum on the surface is the same as that of the clean coating

- Used FIB to cut a cross section through the defect:



Area A, point absorber A1, cross-section analysis



Point absorber cross section

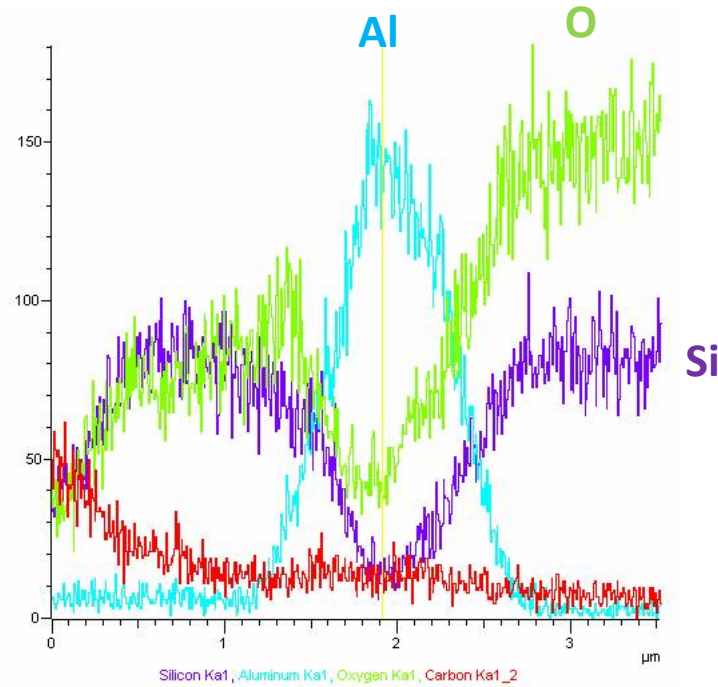
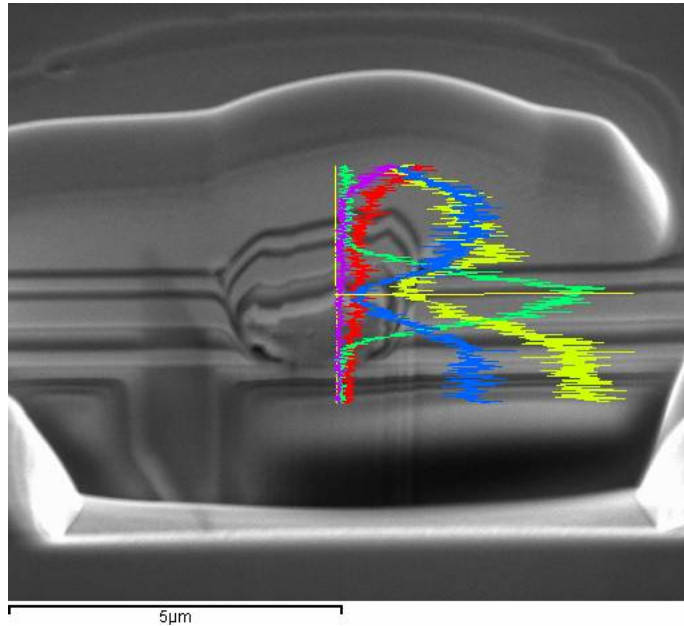
- Coating layer structure is evident
- The ~2 μm absorber was introduced after the first layer and the subsequent layers deposited on top of it
- Bright layers correspond to high index material; dark layers correspond to low index material

Remark: strange AR coating structure:

- Why are layers #1 and #2 made of the same material?
- Number and depths of layers is not consistent with any of the coatings specified by LMA.

Likely Al point absorber

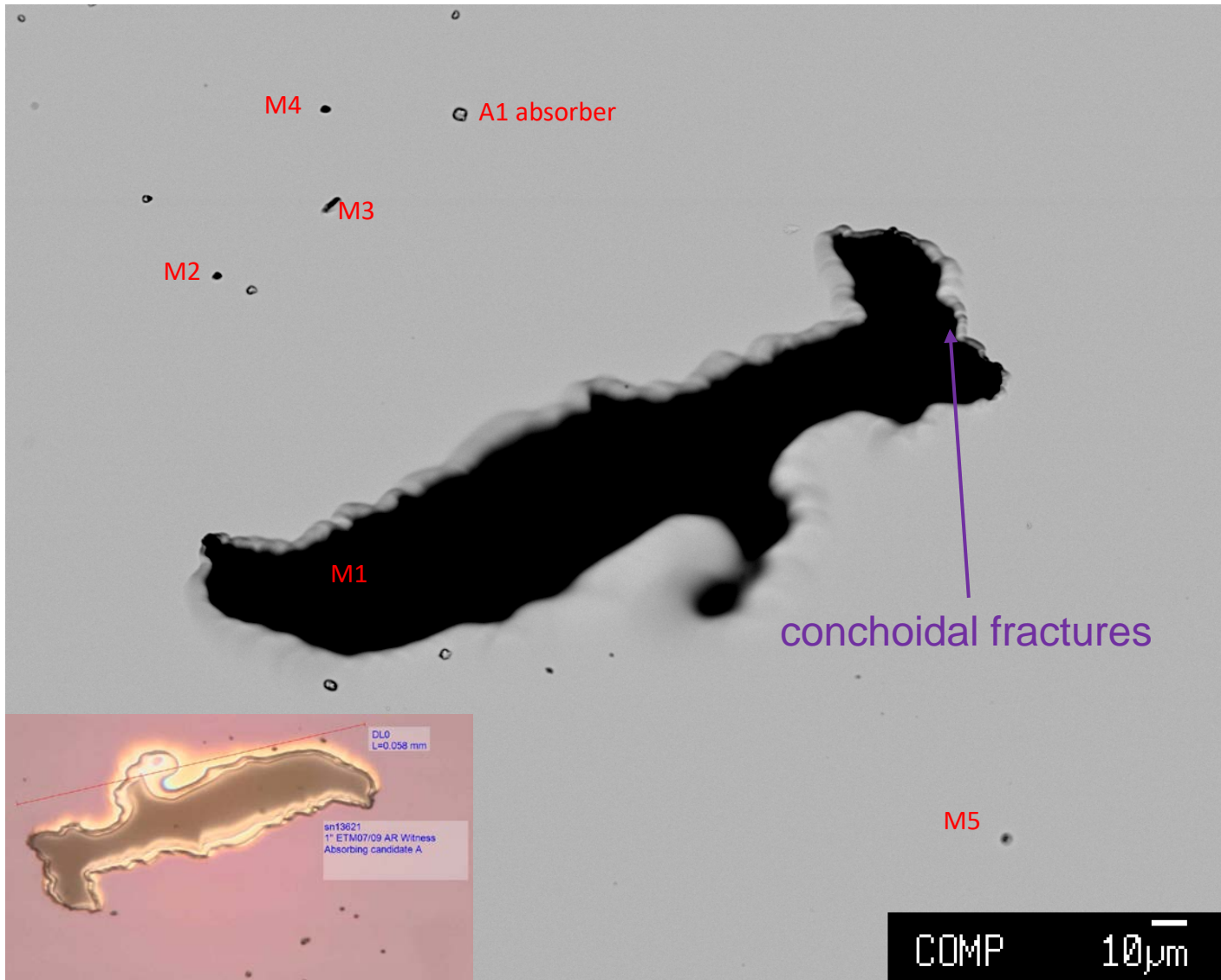
Area A, point absorber A1, line scan



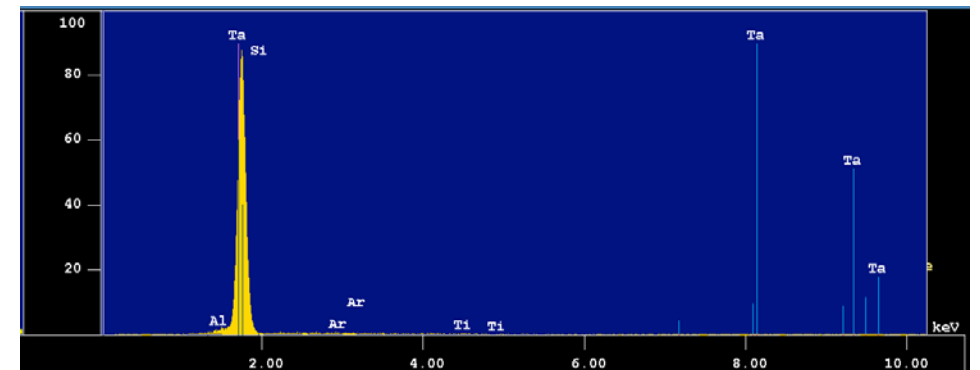
- Strong Al signal at the location of the particle
- Oxygen depletion at the particle location may indicate that we are dealing with pure metal rather than oxide?

There are many more such defects in area A; see slide #7. Are they also caused by Al dust? We are planning to analyze them as well.

Area A, Missing coating

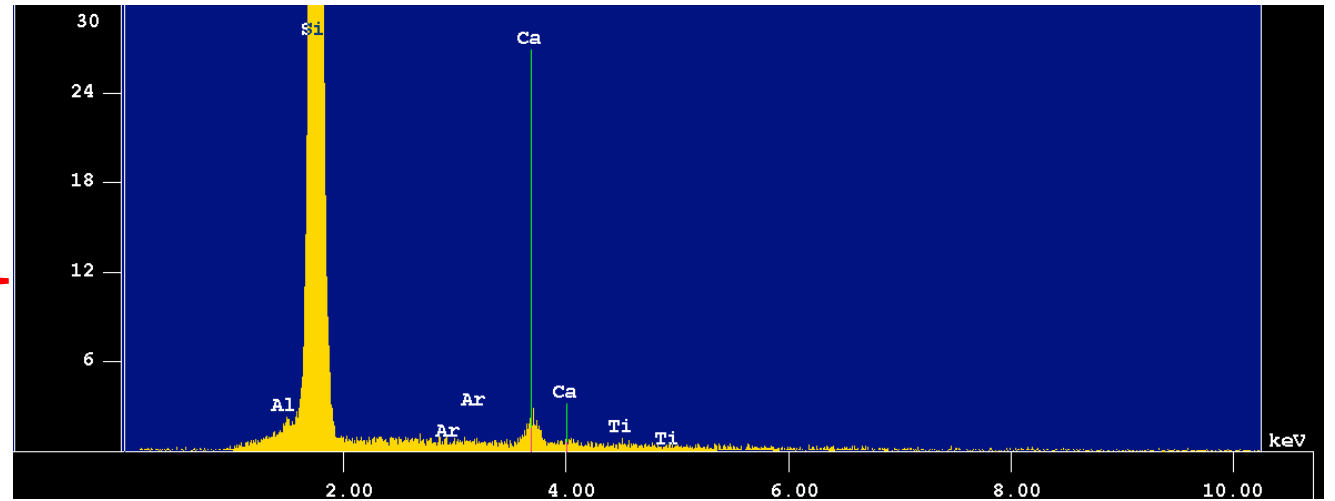
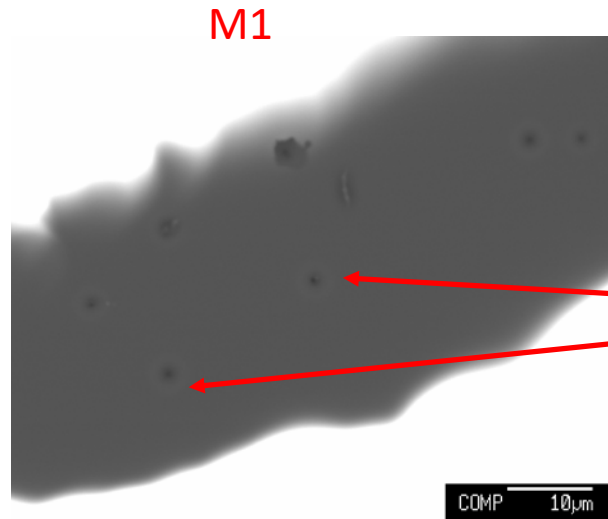


- The missing coating can be easily spotted on large contrast
- 5 places of missing coating with areas of various size, why?
- Conchoidal fractures due to the strain – burst during annealing process?
- Spectrum at M2, M3, and M4 show only Si above 1 keV – pure substrate, but... see next slide

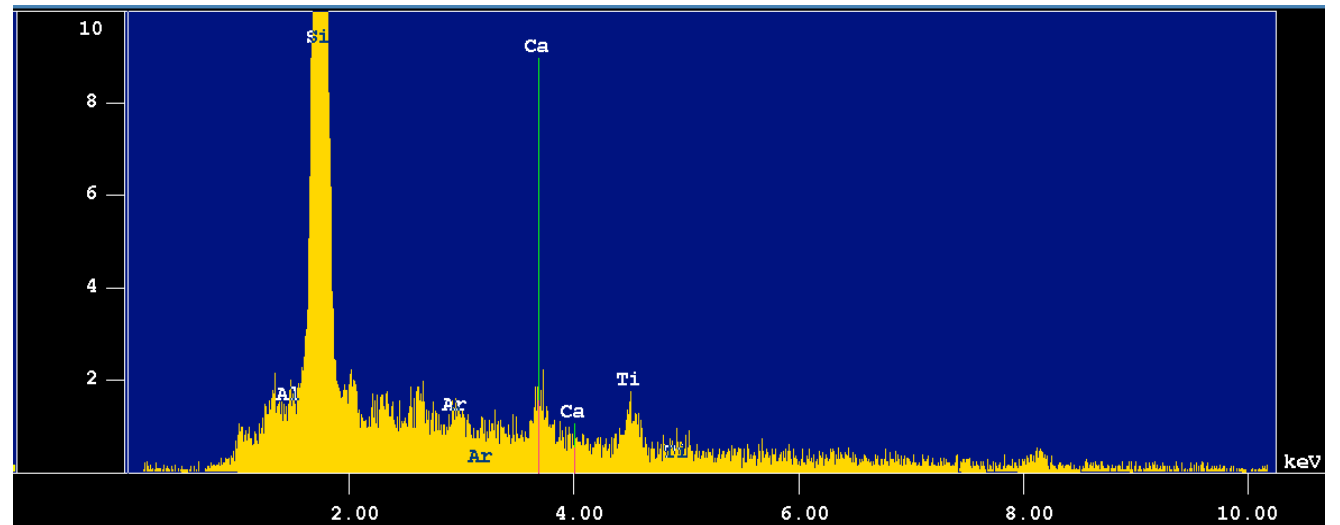
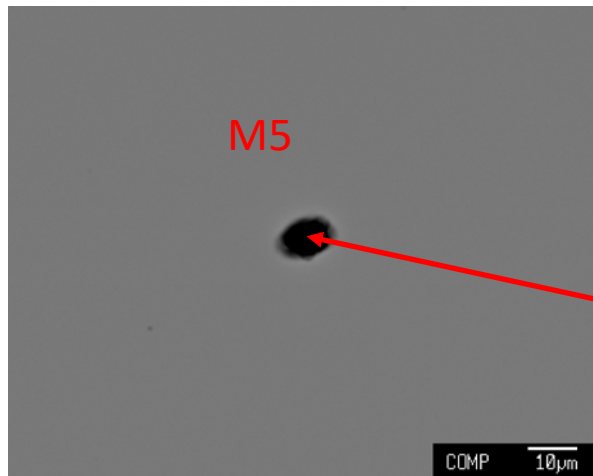


e-beam: 15 kV, 10 nV

Area A, Missing coating, contamination

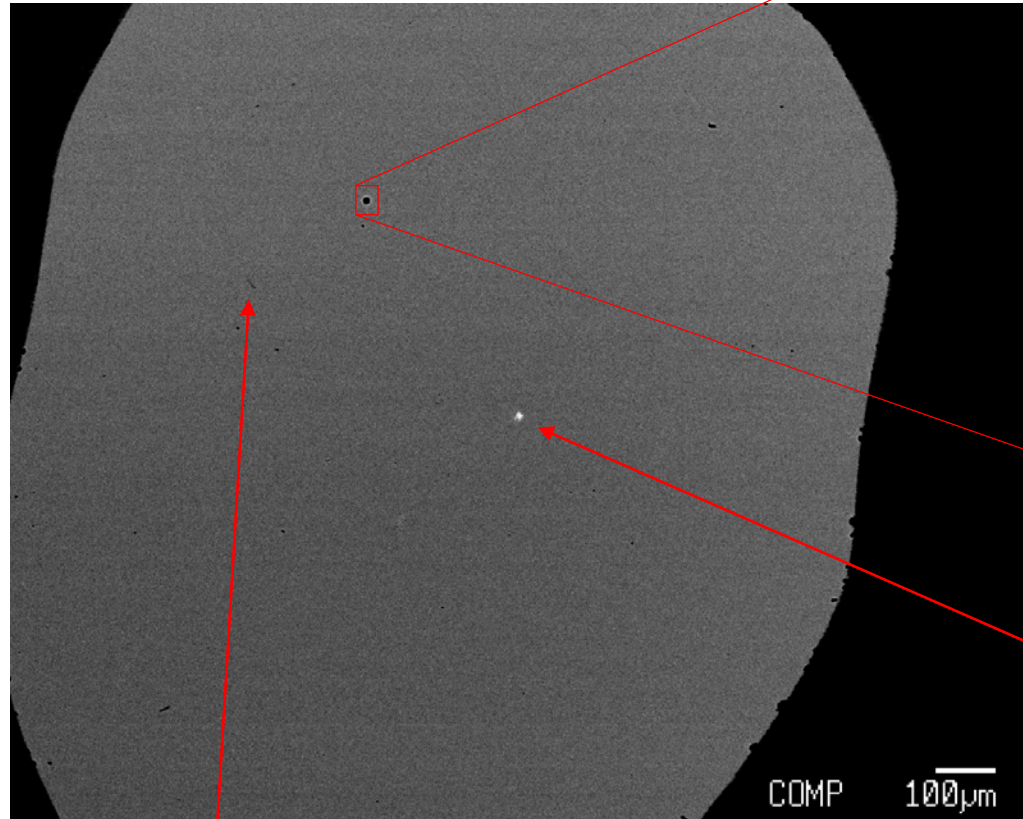


Ca compounds at the bottom of M1 at various locations

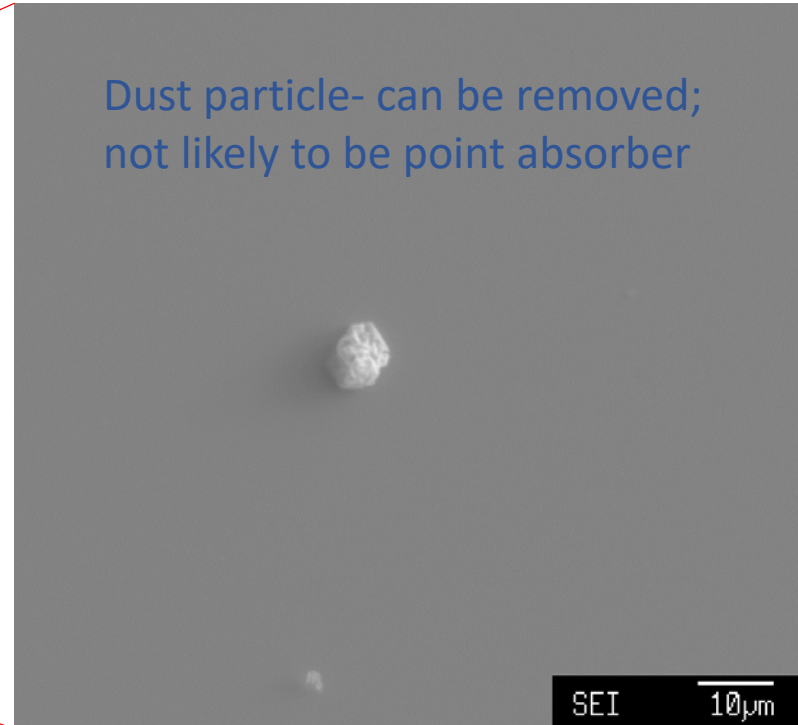


More complex compounds at the bottom of M5

Overview of area C



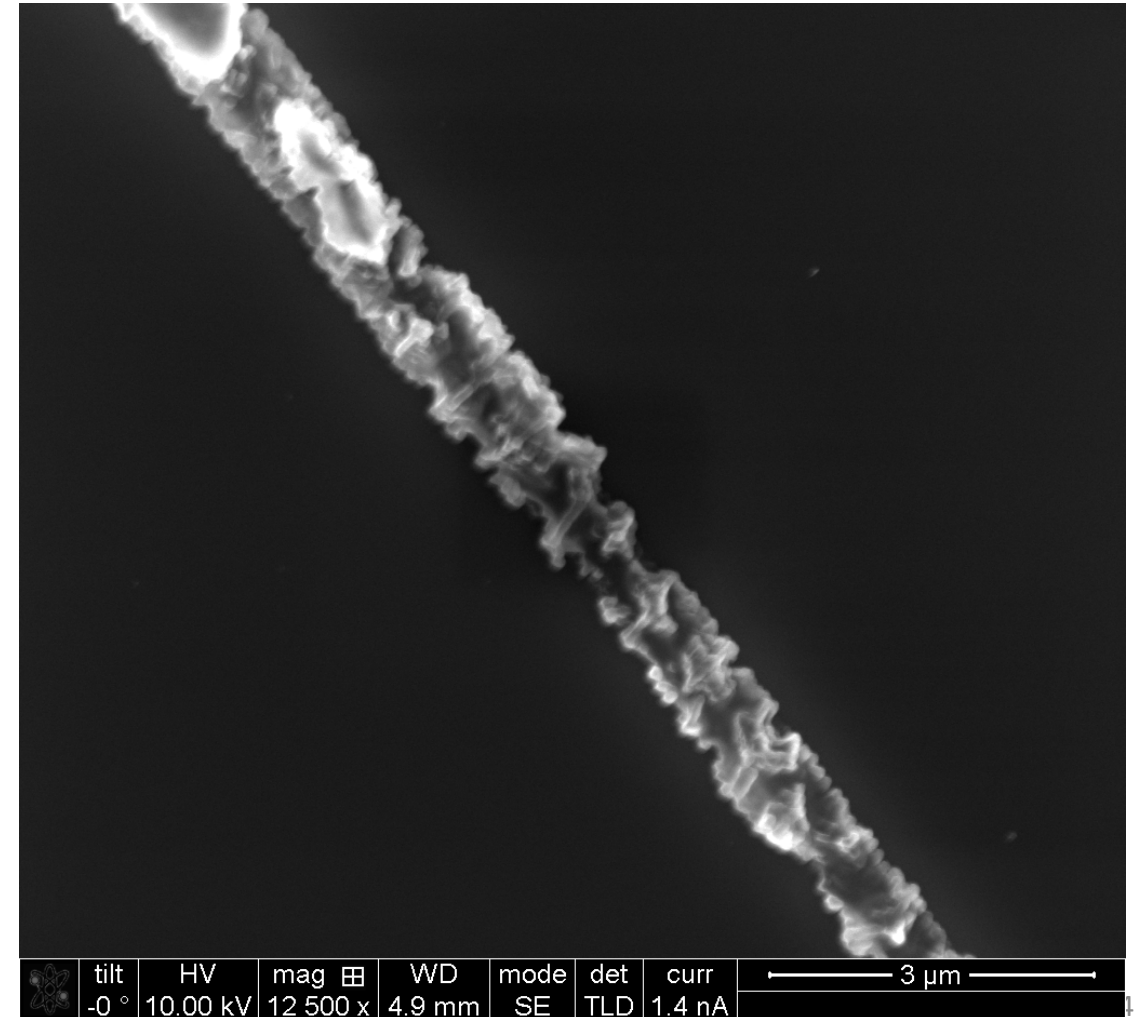
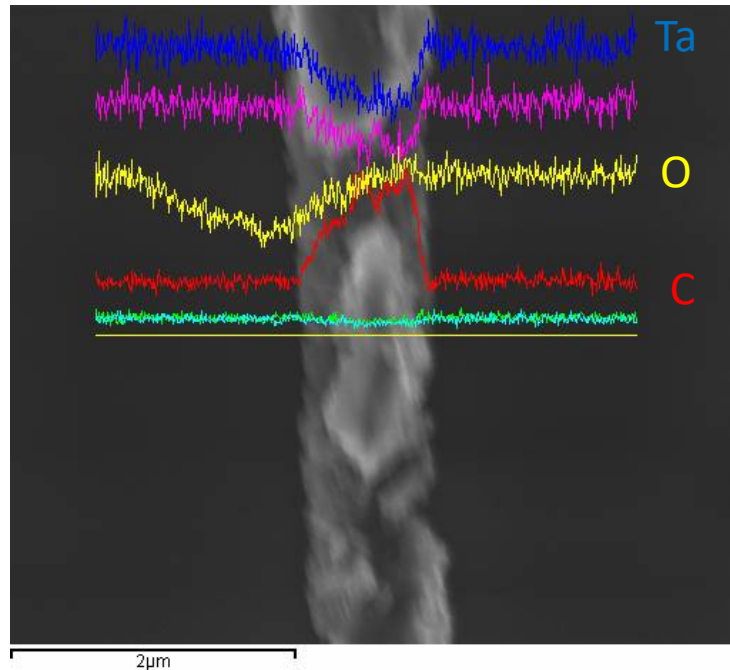
Carbon rod; see next slide



Looks like a flake; spectrum is consistent with that of the clean coating, but we will cut in the future to confirm.

Area C carbon rod

- Absorbing candidate C appears to be a carbon rod
- No evidence of aluminum but we will cut in the future to confirm



Conclusions

- At high absorption locations we found Aluminum particles of size 2-5 μm , most probably metal dust
- Contamination occurs during the coating deposition – one defect found near the surface; one found after the first coating layer
- Origin of the Al dust in the coater is unknown at the moment (mask, ion gun components, shredding of the screws, etc. ?)
- Delamination of the coating may be caused by other contaminants (Ca found in the delamination region)
- Planning on cutting remaining features to investigate Al content under the surface
- Will investigate further absorbing candidates near but outside area C

Thank you Dr. Shiahn Chen for SEM piloting assistance.